

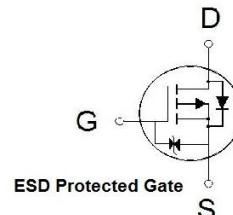
NIKO-SEM

**P-Channel Enhancement Mode
Field Effect Transistor**

PM567EA
SOT-23(S)
Halogen-Free & Lead-Free

**PRODUCT SUMMARY**

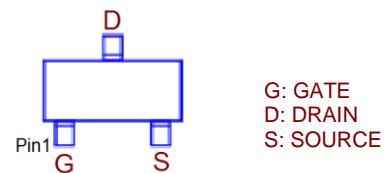
$V_{(BR)DSS}$	$R_{DS(on)}$	I_D
-20V	520m Ω	-0.8A

**Features**

- Pb-Free, Halogen Free and RoHS compliant.
- Low $R_{DS(on)}$ to Minimize Conduction Losses.
- Ohmic Region Good $R_{DS(on)}$ Ratio.
- Optimized Gate Charge to Minimize Switching Losses.
- ESD Protection – HBM Class : 1C.

Applications

- Protection Circuits Applications.
- Logic/Load Switch Circuits Applications.
- Space Limit & Smart Devices Applications.

**ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Gate-Source Voltage	V_{GS}	± 12	V
Continuous Drain Current	I_D	-0.8	A
$T_A = 70^\circ\text{C}$	I_D	-0.64	
Pulsed Drain Current ¹	I_{DM}	-2.1	
Power Dissipation	P_D	0.56	W
$T_A = 70^\circ\text{C}$	P_D	0.36	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient ²	$R_{\theta JA}$		220	°C/W

¹Pulse width limited by maximum junction temperature.

²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper.

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ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-20			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250\mu\text{A}$	-0.4	-0.65	-1.2	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 10\text{V}$			± 30	μA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = -16\text{V}, V_{\text{GS}} = 0\text{V}$			-1	μA
		$V_{\text{DS}} = -10\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 55^\circ\text{C}$			-10	
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = -4.5\text{V}, I_D = -0.45\text{A}$		418	520	$\text{m}\Omega$
		$V_{\text{GS}} = -2.5\text{V}, I_D = -0.1\text{A}$		599	800	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = -5\text{V}, I_D = -0.45\text{A}$		1		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -10\text{V}, f = 1\text{MHz}$		46		pF
Output Capacitance	C_{oss}			18		
Reverse Transfer Capacitance	C_{rss}			9.8		
Total Gate Charge ²	Q_g	$V_{\text{DS}} = -20\text{V}, V_{\text{GS}} = -4.5\text{V}, I_D = -1\text{A}$		1.1		nC
Gate-Source Charge ²	Q_{gs}			0.2		
Gate-Drain Charge ²	Q_{gd}			0.3		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = -10\text{V}, V_{\text{GS}} = -4.5\text{V}$ $I_D \approx -0.45\text{A}, R_G = 5.1\Omega$		17		nS
Rise Time ²	t_r			30		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$			76		
Fall Time ²	t_f			46		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_S				-0.46	A
Forward Voltage ¹	V_{SD}	$I_F = -0.45\text{A}, V_{\text{GS}} = 0\text{V}$			-1.2	V
Reverse Recovery Time	t_{rr}	$I_F = -1\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		46		nS
Reverse Recovery Charge	Q_{rr}			28		nC

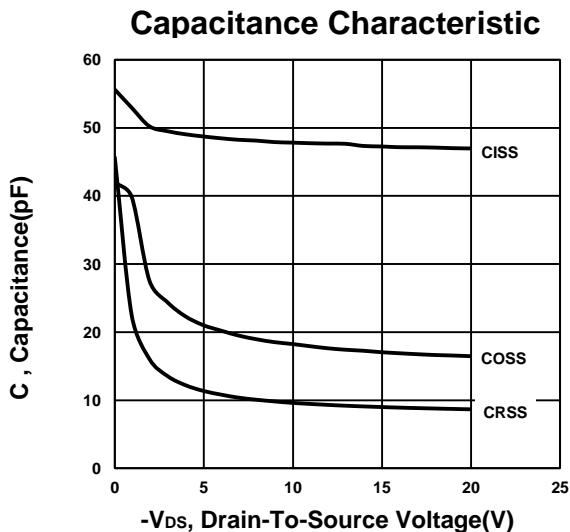
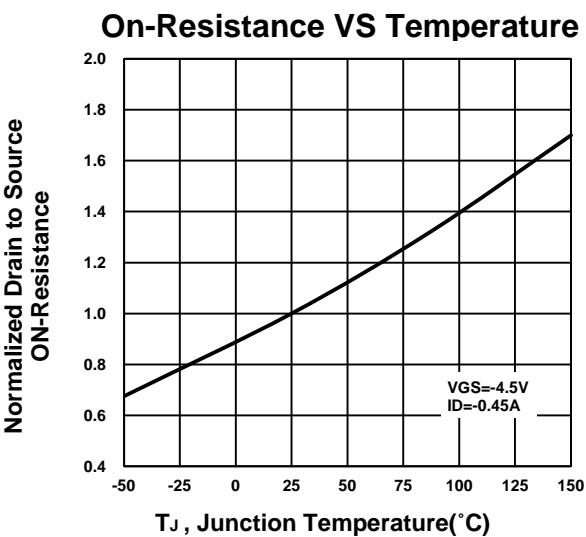
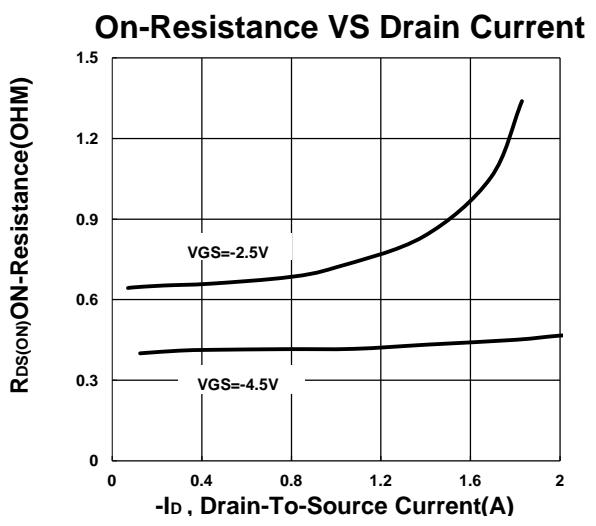
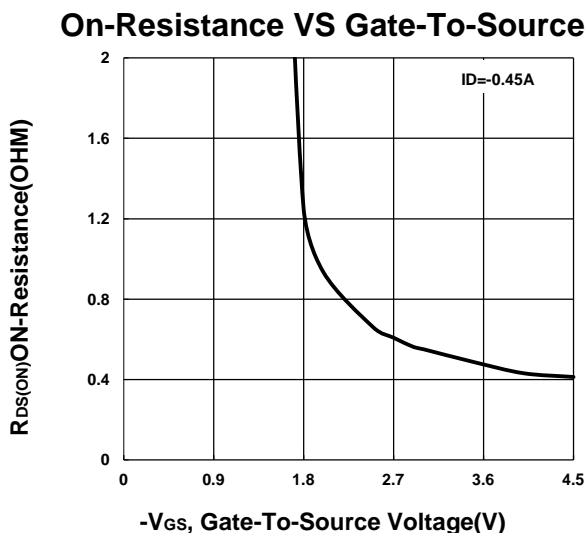
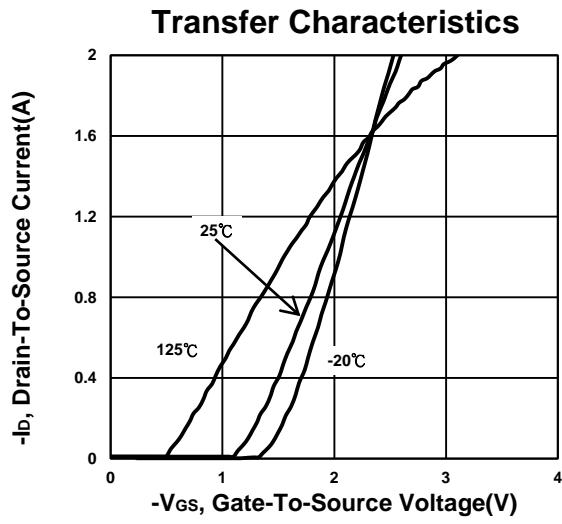
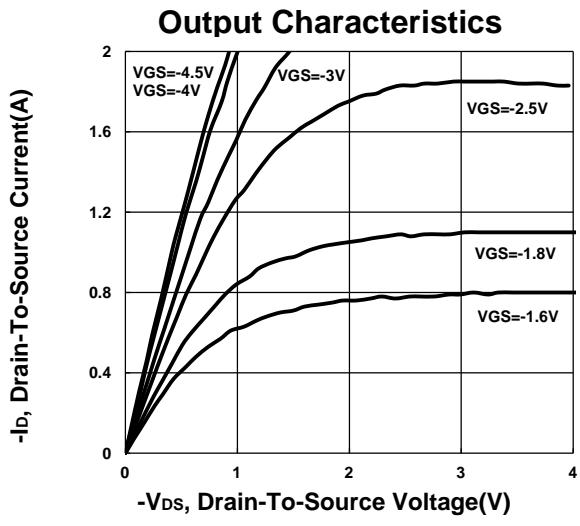
¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

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